TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# T C 7 M E T 5 7 3 A F K

Octal D-Type Latch with 3-State Output

The TC7MET573AFK is an advanced high speed CMOS octal latch with 3-state output fabricated with silicon gate  $C^2MOS$  technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This 8-bit D-type latch is controlled by a latch enable input (LE) and a output enable input ( $\overline{OE}$ ).

When the  $\overline{OE}$  input is high, the eight outputs are in a high impedance state.

The input voltage are compatible with TTL output voltage.

This device may be used as a level converter for interfacing 3.3 V to 5 V system.

Input protection and output circuit ensure that 0 to 5.5 V can be applied to the input and output (\*) pins without regard to the supply voltage. These structure prevents device destruction due to mismatched supply and input/output voltages such as battery back up, hot board insertion, etc.

\*: output in off state

#### Features

- High speed:  $t_{pd} = 7.7 \text{ ns} (typ.) (V_{CC} = 5 \text{ V})$
- Low power dissipation:  $I_{CC} = 4 \mu A (max) (Ta = 25^{\circ}C)$
- Compatible with TTL outputs: VIL = 0.8 V (max)

 $V_{IH} = 2.0 V (min)$ 

- Power down protection is provided on all inputs and outputs.
- Balanced propagation delays:  $t_{pLH} \simeq t_{pHL}$
- Low noise:  $V_{OLP} = 1.5 V (max)$
- Pin and function compatible with the 74 series (74AC/HC/F/ALS/LS etc.) 573 type.



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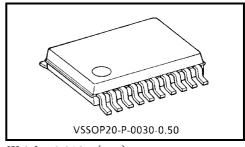
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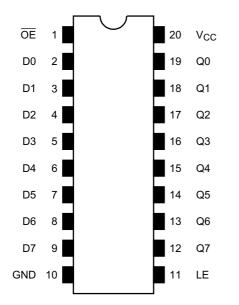
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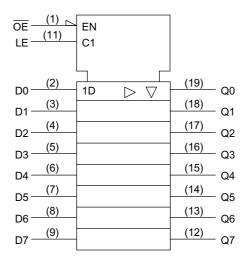
Weight: 0.016 g (typ.)

# <u>TOSHIBA</u>

#### Pin Assignment (top view)



#### **IEC Logic Symbol**



#### Truth Table

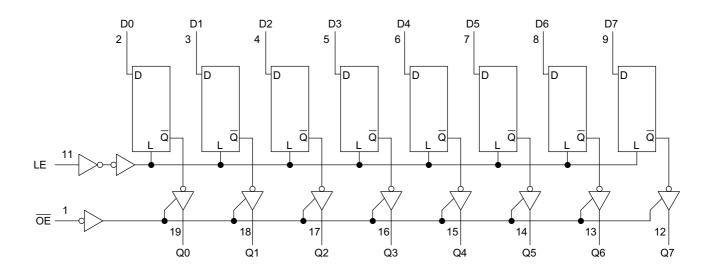
	Outputs		
ŌĒ	LE	D	Outputs
Н	Х	Х	Z
L	L	Х	Q <sub>n</sub>
L	Н	L	L
L	Н	Н	Н

X: Don't care

Z: High impedance

 $\mathsf{Q}_n\!\!:\mathsf{Q}$  outputs are latched at the time when the LE input is taken to a low logic level.

#### System Diagram



#### **Maximum Ratings**

Characteristics	Symbol	Rating	Unit
Supply voltage range	V <sub>CC</sub>	-0.5~7.0	V
DC input voltage	V <sub>IN</sub>	-0.5~7.0	V
DC output voltage	Vout	-0.5~7.0 (Note1)	V
DC output voltage	VOUT	-0.5~V <sub>CC</sub> + 0.5 (Note2)	v
Input diode current	I <sub>IK</sub>	-20	mA
Output diode current	IOK	±20 (Note3)	mA
DC output current	IOUT	±25	mA
DC V <sub>CC</sub> /ground current	ICC	±75	mA
Power dissipation	PD	180	mW
Storage temperature	T <sub>stg</sub>	-65~150	°C

Note1: Output is off-state

Note2: High or low state. IOUT absolute maximum rating must be observed.

Note3:  $V_{OUT} < GND, V_{OUT} > V_{CC}$ 

#### **Recommended Operating Conditions**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	4.5~5.5	V
Input voltage	V <sub>IN</sub>	0~5.5	V
Output voltage	Maxim	0~5.5 (Note4)	V
Output voltage	Vout	0~V <sub>CC</sub> (Note5)	v
Operating temperature	T <sub>opr</sub>	-40~85	°C
Input rise and fall time	dt/dv	0~20	ns/V

Note4: Output in off state

Note5: High or low state

#### **Electrical Characteristics**

#### **DC Characteristics**

Characteristics		Symbol Test Condition			-	Ta = 25°C			Ta = -40~85°C		
Characte	aracteristics Symbol		Test	Test Condition		Min	Тур.	Max	Min	Max	Unit
Input voltage	High level	VIH		_	4.5~5.5	2.0	_	_	2.0	_	V
input voltage	Low level	VIL		_	4.5~5.5	_	_	0.8	_	0.8	v
	High level	Varia	$V_{IN} = V_{IH}$	I <sub>OH</sub> = -50 μA	4.5	4.4	4.5	_	4.4	_	V
Output voltage	riigirievei	V <sub>OH</sub>	or V <sub>IL</sub>	I <sub>OH</sub> = -8 mA	4.5	3.94	_	_	3.80	_	
Output voltage	Low level	V <sub>OL</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OL} = 50 \ \mu A$	4.5	_	0	0.1	—	0.1	
				$I_{OL} = 8 \text{ mA}$	4.5		_	0.36	_	0.44	
3-state output of	f-state current	I <sub>OZ</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$ $V_{OUT} = V_{CC}$ or GND		5.5	-	_	±0.25	_	±2.50	μΑ
Input leakage cu	rrent	I <sub>IN</sub>	V <sub>IN</sub> = 5.5	V or GND	0~5.5	_	_	±0.1	_	±1.0	μA
Quiescent supply current		I <sub>CC</sub>	$V_{IN} = V_{CC}$ or GND		5.5	_	_	4.0	_	40.0	μA
		Ісст	Per input: $V_{IN} = 3.4 V$ Other input: $V_{CC}$ or GND		5.5	_	_	1.35	_	1.50	mA
Output leakage of	current	I <sub>OPD</sub>	V <sub>OUT</sub> = 5.5 V		0		—	0.5	_	5.0	μA

## Timing Requirements (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics Symbol	Symbol	Test Condition	ndition		25°C	Ta = −40~85°C	Unit
	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Limit	Unit	
Minimum pulse width (LE)	t <sub>w (H)</sub> t <sub>w (L)</sub>	_	$5.0\pm0.5$	_	6.5	8.5	ns
Minimum set-up time	ts	—	$5.0\pm0.5$	_	1.5	1.5	ns
Minimum hold time	t <sub>h</sub>	—	$5.0\pm0.5$		3.5	3.5	ns

### AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics Symt	Symbol	Test Condition				Ta = 25°C			Ta = -40~85°C	
	Symbol	Test Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Min	Max	Unit
Propagation delay time	t <sub>pLH</sub>		5.0 ± 0.5	15	_	7.7	12.3	1.0	13.5	ns
(LE-Q)	t <sub>pHL</sub>		5.0 ± 0.5	50	_	8.5	13.3	1.0	14.5	115
Propagation delay time	t <sub>pLH</sub>		$50 \pm 0.5$	15		5.1	8.5	1.0	9.5	ns
(D-Q)	t <sub>pHL</sub>		5.0 ± 0.5	50	_	5.9	9.5	1.0	10.5	115
	t <sub>pZL</sub>	$R_L = 1 k\Omega$	$5.0\pm0.5$	15		6.3	10.9	1.0	12.5	ns
	t <sub>pZH</sub>	NL - 1 K22		50		7.1	11.9	1.0	13.5	
3-state output disable time	t <sub>pLZ</sub> t <sub>pHZ</sub>	$R_L = 1 \ k\Omega$	$5.0\pm0.5$	50		8.8	11.2	1.0	12.0	ns
Output to output skew	t <sub>osLH</sub> t <sub>osHL</sub>	(Note6)	$5.0\pm0.5$	50		_	1.0	_	1.0	ns
Input capacitance	C <sub>IN</sub>			_	4	10	_	10	pF	
Output capacitance	C <sub>OUT</sub>	_		_	9	_			pF	
Power dissipation capacitance	C <sub>PD</sub>			(Note7)		25			_	pF

Note6: Parameter guaranteed by design.

 $t_{osLH} = |t_{pLHm} - t_{pLHn}|, t_{osHL} = |t_{pHLm} - t_{pHLn}|$ 

Note7: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8$  (per latch)

And the total  $C_{\mbox{PD}}$  when n pcs. of latch operate can be gained by the following equation:

C<sub>PD</sub> (total) = 14 + 11 · n

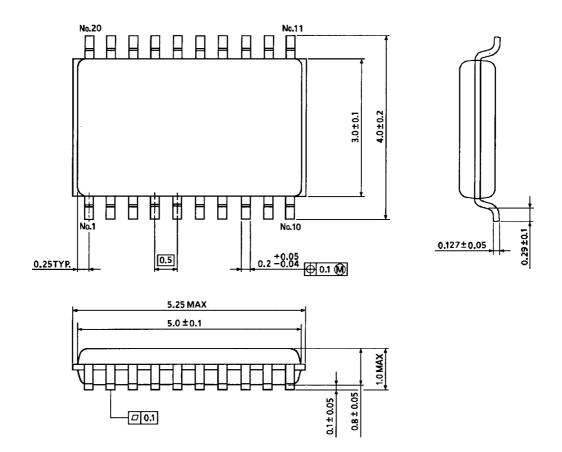
#### Noise Characteristics (Input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition	_	Ta = 25°C		- Unit
Characteristics	Symbol	Test Condition	$V_{CC}\left(V\right)$	Тур.	Limit	Unit
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	$C_L = 50 \text{ pF}$	5.0	1.1	1.5	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	$C_L = 50 \text{ pF}$	5.0	-1.1	-1.5	V
Minimum high level dynamic input voltage $~V_{\rm IH}$	VIHD	$C_L = 50 \text{ pF}$	5.0	_	2.0	V
Maximum low level dynamic input voltage $V_{IL}$	V <sub>ILD</sub>	C <sub>L</sub> = 50 pF	5.0	_	0.8	V

### **Package Dimensions**

VSSOP20-P-0030-0.50

Unit : mm



Weight: 0.03 g (typ.)